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- (71) Applicant: **NORDSON CORPORATION** [US/US];
28601 Clemens Road, Westlake, OH 44145-1119 (US).
- (72) Inventors: **WALKER, Bill**; 5-6 School Barn Cottages
Pentlow, Sudbury, Suffolk CO10 7JN (GB). **SUTTON,**
- David**; 7 Ian Rose Drive, Stanway, Colchester, Essex CO3
0AT (GB).
- (74) Agent: **HILTEN, John, S.** et al.; Baker & Hostetler LLP,
2929 Arch Street, Cira Centre, 12th Floor, Philadelphia, PA
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(54) Title: AN X-RAY INSPECTION SYSTEM, AN X-RAY IMAGING ACCESSORY, A SAMPLE SUPPORT, A KIT, AND A METHOD OF USING AN X-RAY INSPECTION SYSTEM

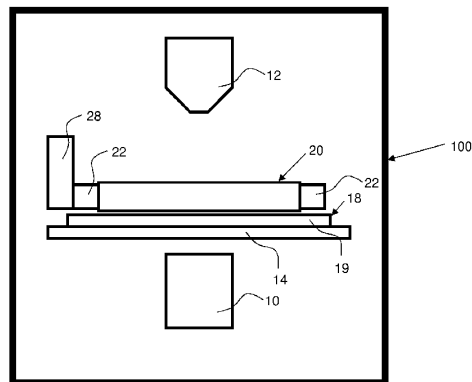


Figure 1

(57) Abstract: An x-ray inspection system (100) comprising an x-ray source (10), an x-ray detector (12), a sample support comprising a pliable material and a sample support positioning assembly configured to position the sample support (20) between the x-ray source (10) and the x-ray detector (12). The sample support (20) is configured to removably clamp a sample for inspection in a fixed position with respect to the sample support and configured so that, in use, at least one surface of the sample is in contact with the pliable material. The sample support positioning assembly comprises a rotational drive (28) configured to rotate the sample support about a rotational axis. This allows the sample to be rotated about a rotational axis such that a series of two-dimensional images can be captured by the x-ray detector that can be used to create a three-dimensional reconstruction of the sample.

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